



OIML Certification System (OIML-CS) Implementation Accreditation in Legal Metrology

Legal Metrology Experts

Legal Metrology Experts validated by the OIML-CS Management Committee to participate in Accreditation and Peer Assessments under the OIML-CS

Expert Name	Country	OIML Recommendation																			Assessment Experience		
		R 16	R 21	R 46	R 49	R 50	R 51	R 60	R 61	R 75	R 76	R 85	R 99	R 106	R 107	R 117	R 126	R 129	R 134	R 137	R 139	ISO/IEC 17025	ISO/IEC 17065
Petra Milota	AT				✓																	✓	✓
Yi Chen	AU					✓	✓	✓			✓											✓	
Mario Zamora	AU																						
Dirk Bils	BE																						✓
Gulian Couvreur	CH						✓	✓	✓		✓			✓	✓							✓	✓
Juan Carlos Mateus Sanchez	BR	✓	✓	✓							✓		✓			✓	✓					✓	
Luciano Bruno Faruolo	BR										✓											✓	
Wang Jian	CN						✓				✓											✓	
Hu Manhong	CN					✓	✓		✓		✓												✓
Jiang Jile	CN							✓															
Shi Leibing	CN			✓																			
Yang Jing	CN															✓							
Yang Youtao	CN																						✓
Zhong Ruilin	CN					✓	✓		✓		✓				✓								✓
Zhou Shaoyuan	CN			✓																			

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Miroslava Benkova	CZ				✓										✓							✓		
Ivan Kriz	CZ					✓	✓		✓		✓			✓	✓					✓			✓	
Tomás Valenta	CZ																			✓			✓	✓
Jakub Vacula	CZ														✓								✓	
Timo Schwabe	DE						✓																	
Christophe Brun	FR														✓							✓		✓
Denis Vogel	FR					✓	✓	✓	✓		✓				✓								✓	
Emeric Morel	FR				✓																		✓	
Luc Lopez*	FR		✓				✓			✓	✓	✓			✓									✓
Reuven Perez	IL				✓																		✓	
Ashutosh Agarwal	IN				✓		✓				✓												✓	
Luico Zotti	IT				✓																		✓	✓
Nobuhiko Azami	JP							✓																
Shinsuke Mikura	JP							✓															✓	
Tomohiro Nagano	JP										✓												✓	
Satoshi Otani	JP										✓												✓	
Takeshi Ito	JP														✓								✓	
Erik Beumer	NL				✓				✓		✓				✓								✓	
Marc Schmidt	NL														✓							✓		✓
Marcel Cloo	NL			✓																			✓	
Paul van Rooij	NL				✓										✓								✓	
Roy Scholten	NL						✓		✓		✓				✓				✓				✓	
Baris Yilmaz	NL						✓				✓								✓				✓	✓
Hans Boereboom	NL			✓																				
Paul Kok	NL		✓			✓	✓		✓		✓		✓		✓		✓	✓	✓				✓	✓
Carl Van Wijngaarden	NL																				✓		✓	
Aldemar Tjoa	NL			✓	✓		✓				✓				✓		✓		✓				✓	
Mathias Meijer	NL		✓					✓			✓												✓	✓

* limited to assessments of OIML Issuing Authorities

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Yvo Vermeul	NL										✓										✓			
Srinivas Bobbala	NZ										✓					✓							✓	
Hakan Källgren	SE					✓	✓	✓	✓		✓			✓	✓								✓	✓
Matej Grum	SI					✓	✓		✓		✓			✓	✓								✓	✓
Aleksander Premuš	SI		✓	✓																			✓	✓
Bülent Aydemir	TR					✓	✓	✓	✓		✓			✓	✓						✓		✓	
Sevda Kaçmaz	TR					✓	✓	✓	✓		✓			✓	✓						✓		✓	
Marek Bokota	UK				✓																		✓	✓
Wei Ji	UK							✓															✓	✓
Gregory Glas	UK		✓				✓				✓												✓	✓
Jaco Hattingh	ZA				✓						✓												✓	